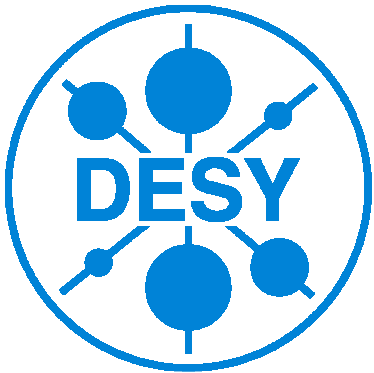
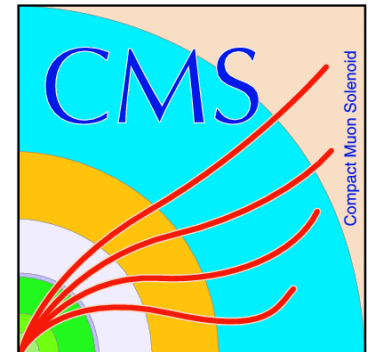


Alignment Position Error (APE) Estimation using Width of Normalized Residual Distributions



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Hamburg Alignment Meeting
16.11.2010



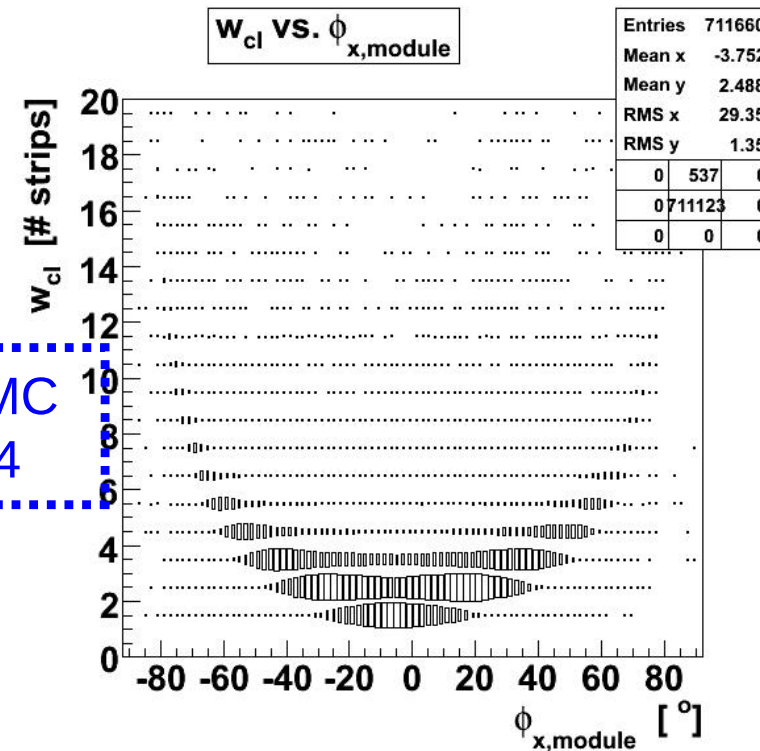
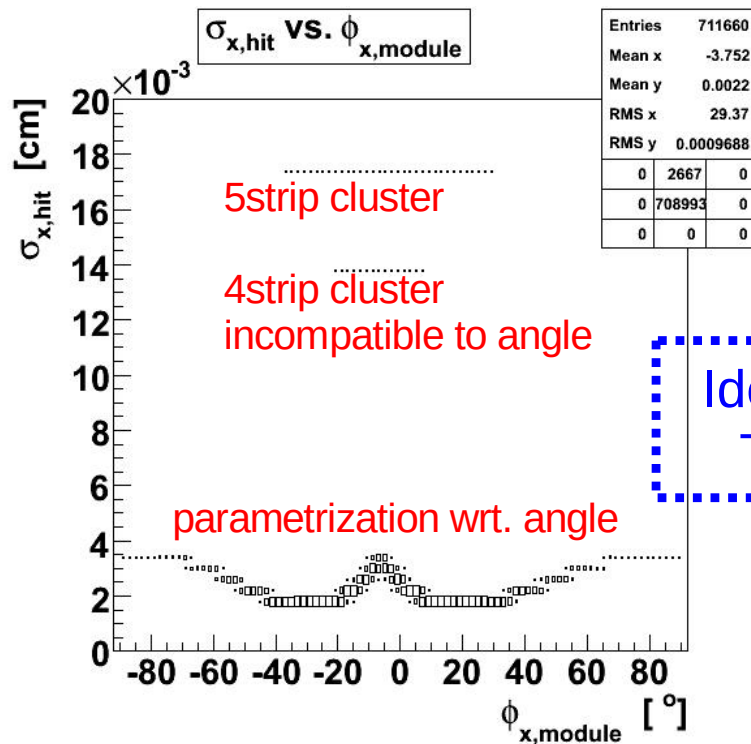
Overview

- Implementation of APE in track reconstruction
- Influence of misalignment on normalized residuals
- Method of APE estimation from normalized residual distributions
- Setup of simulated MC events and misalignment
- Results

Hit reconstruction

- Local reconstruction with cluster parameter estimator (CPE):
Current implementation for **Hit /**
 - Position x_{hit} as **barycentre** of strip charges of clusters
 - Error σ_{hit} based on track **incident angle** ϕ_{module} (almost) regardless of cluster width w_{cl} and shape
 - If cluster is wider than track projection allows, huge error assigned

$$\sigma_{\text{hit}} = w_{\text{cl}} \cdot \text{pitch} \cdot \sqrt{12}$$



Implementation of alignment precision in track reconstruction

- Global reconstruction
 - Depending strongly on alignment parameters $\mathbf{p}$
 - Track j – parametrisation $\mathbf{q}$ leading to track prediction x_{track} and error σ_{track}
 - Uncertainty of alignment parameters σ_{align} – inclusion in track reco:
 - 2 translations (σ_x, σ_y) in module's plane
 - Quadratical addition to intrinsic resolution per coordinate
- $$\sigma_{\text{eff}}^2 = \sigma_{\text{hit}}^2 + \sigma_{\text{align}}^2$$
- Individual values for every module possible

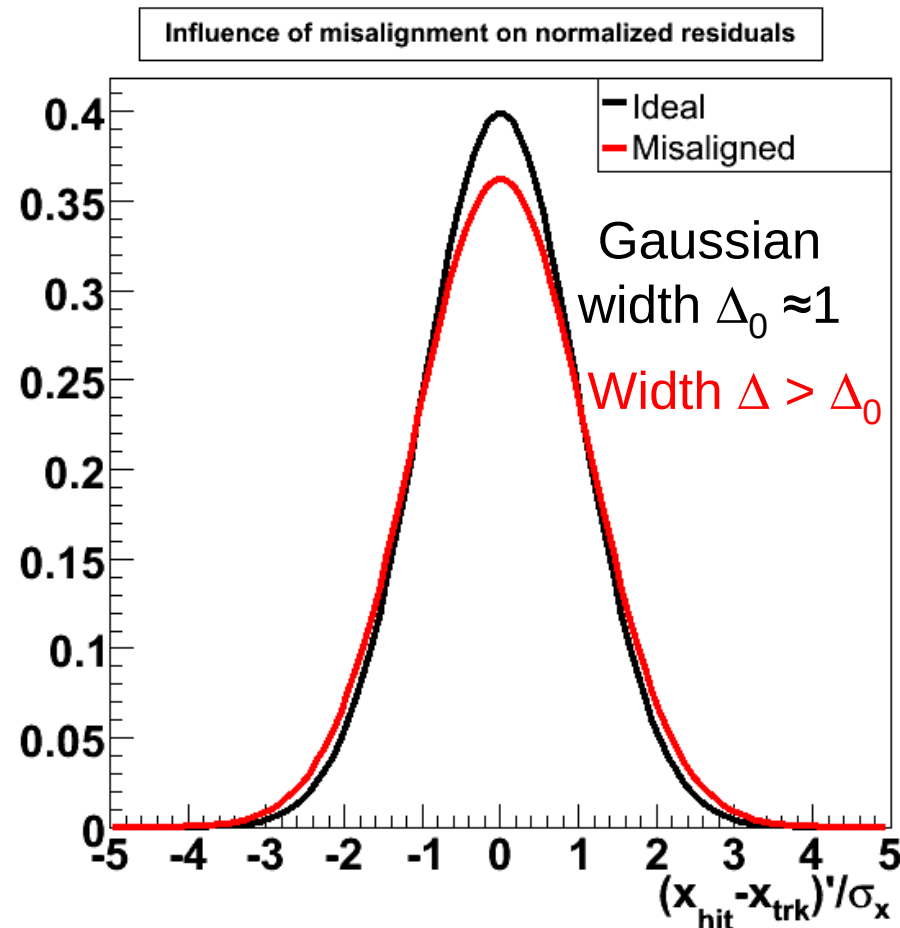
Normalized residuals and misalignment I

- Regard residuals with hit under study excluded from track fit
 - Errors of track and hit become independent

$$\frac{r_{ji}}{\sigma_{ji,\text{tot}}} = \sigma_{ji,\text{tot}}^{-1} \left(x'_{ji,\text{track}}(\mathbf{p}, \mathbf{q}_j) - x'_{ji,\text{hit}} \right)$$

$$\begin{aligned} \sigma_{\text{tot}}^2 &= \sigma_{\text{track}}^2 + \sigma_{\text{eff}}^2 \\ &= \sigma_{\text{track}}^2 + \sigma_{\text{hit}}^2 + \sigma_{\text{align}}^2 \end{aligned}$$

- Perfect alignment:
approx. gaussian with
width $\Delta_0 \approx 1$
- Also non-gaussian effects
present
- Misalignment:
Refit tracks with APE set
to zero
 - Broadened width Δ is
measure for misalignment

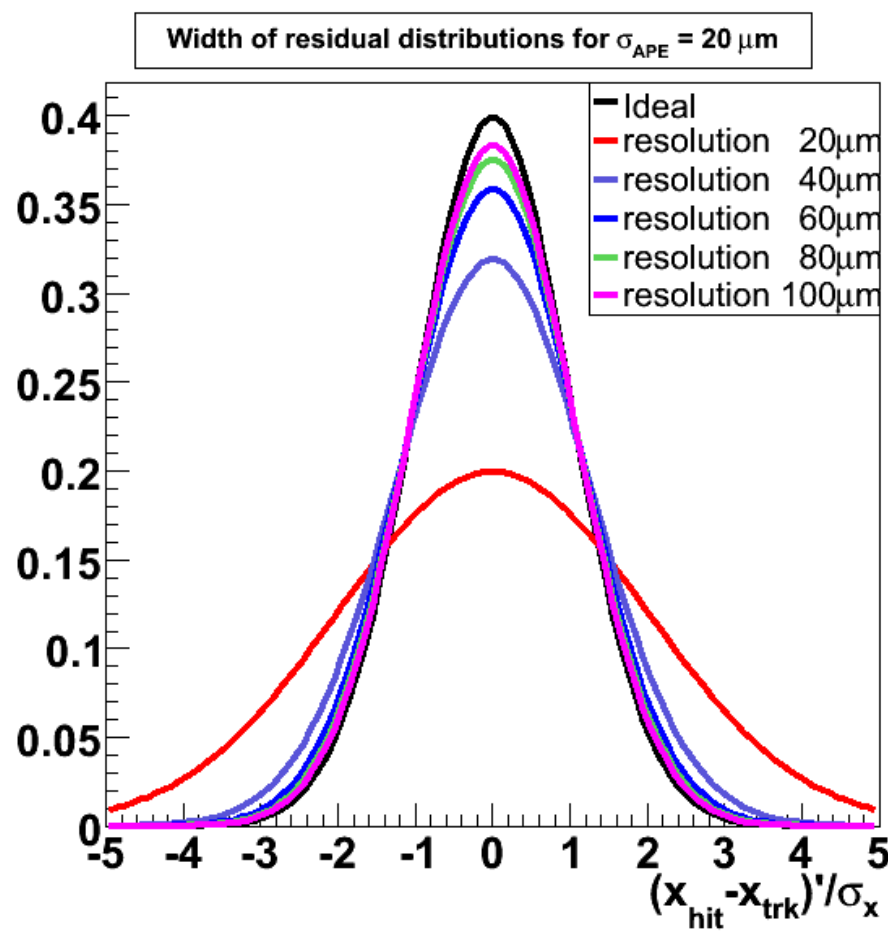
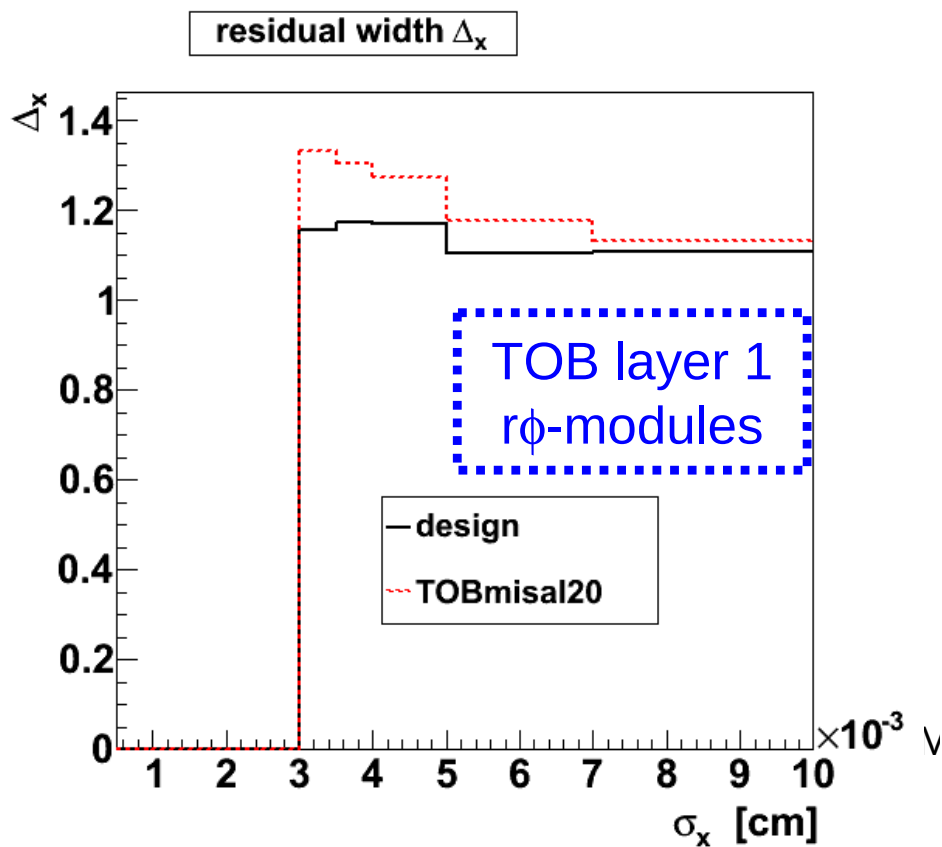


Normalized residuals and misalignment II

- But: influence of misalignment depends on residual resolution σ (without APE)

$$\sigma^2 = \sigma_{\text{track}}^2 + \sigma_{\text{hit}}^2$$

- Need to regard normalized residual distribution in small intervals of residual resolution



Method for estimating alignment precision

- Regard 10 different residual resolution intervals independent
- Take width Δ_i from ideal MC (fit gaus to core distribution)
 - Ideal width Δ_0 : (Entry*resolution^2)-weighed mean over all intervals
- Take broadened width Δ from data (fit gaus to core distribution)
- Estimate **alignment precision**, so that residual error σ reduces width to ideal value

$$\Delta \cong \Delta_0$$

$$\begin{aligned}\sigma^2 &= \sigma_{\text{track}}^2 + \sigma_{\text{eff}}^2 \\ &= \sigma_{\text{track}}^2 (\sigma_{\text{align}}) + \sigma_{\text{hit}}^2 + \sigma_{\text{align}}^2\end{aligned}$$

Correlation of errors
of all hits per track
→ iterations necessary

- For $\sigma \sim \text{constant}$ it is valid:

$$\sigma_{\text{Align}} = \sqrt{(\Delta^2 - \Delta_0^2)} \cdot \sigma$$

- Calculate APE per bin and take entry-weighted mean

Setup of MC analysis

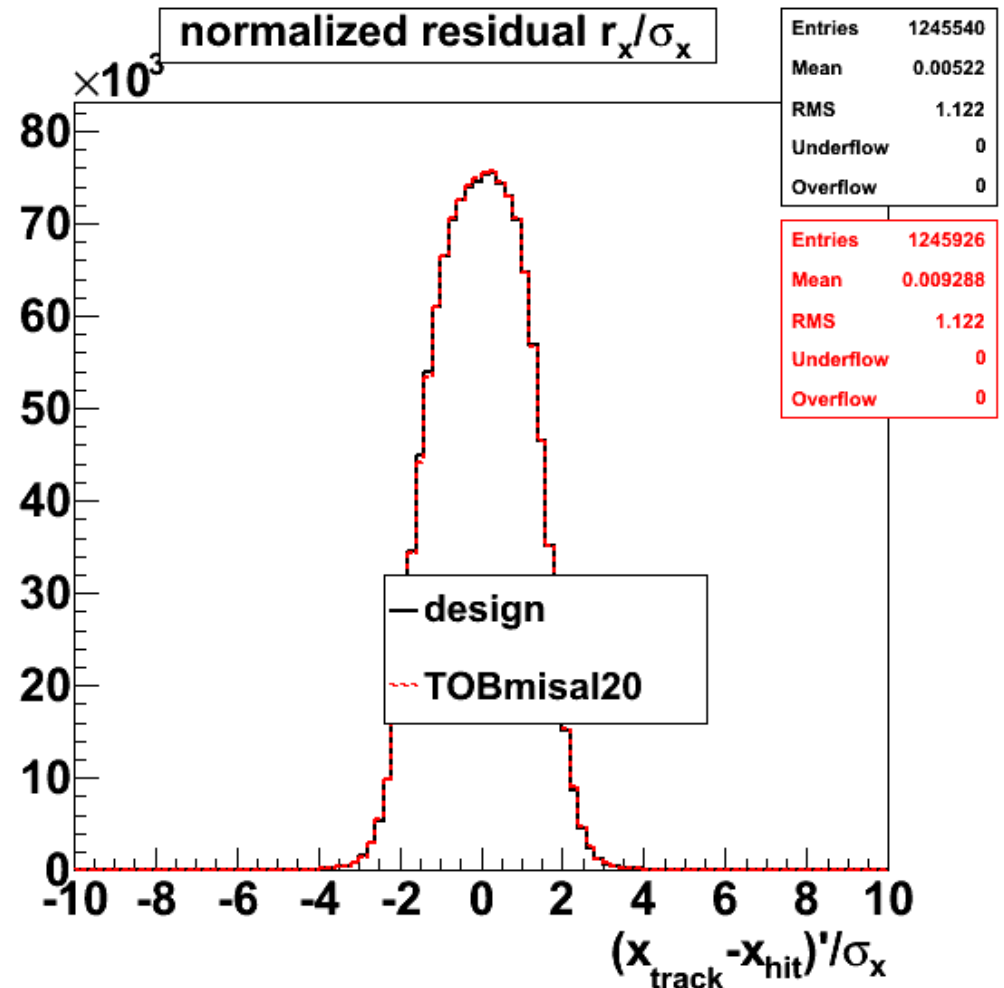
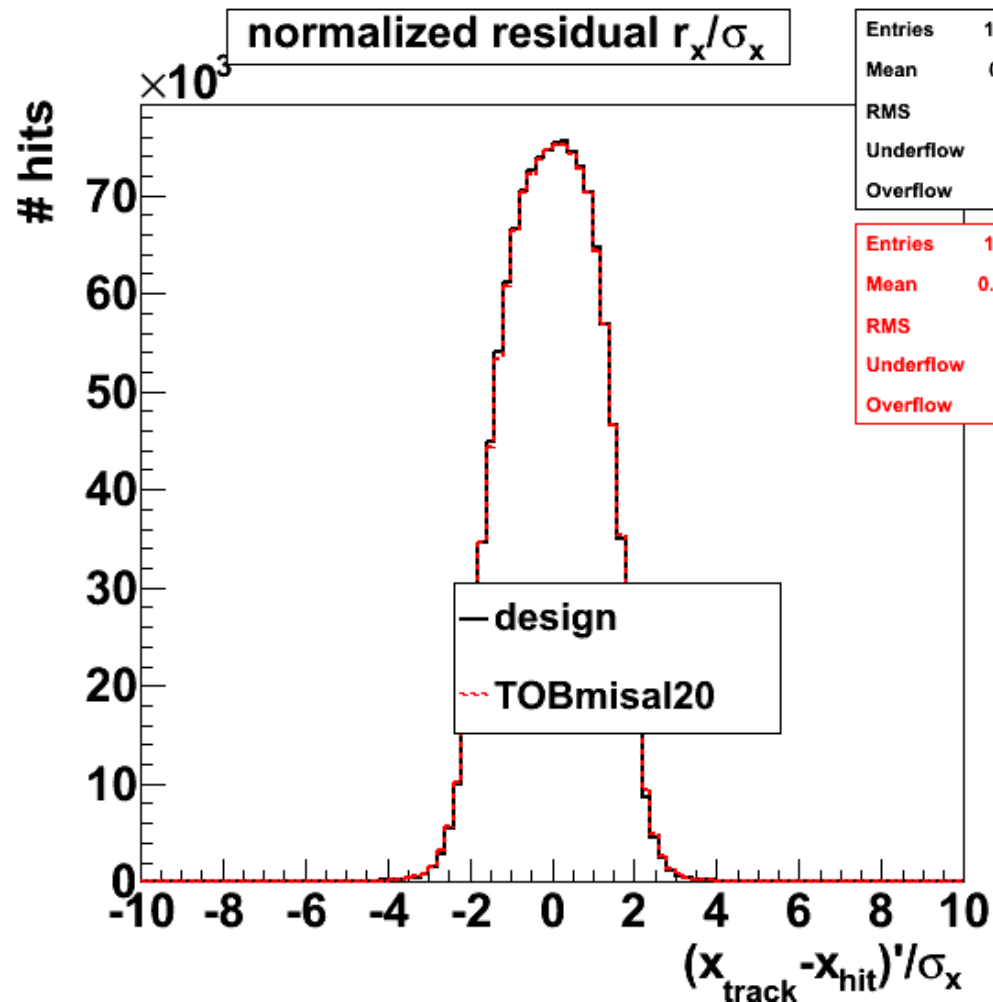
- 10 mio. Events generated with particle gun with $10\text{GeV} < p < 300\text{GeV}$, and flat in η
(Ideal conditions, design geometry, vertex smearing)
 - Simulated 5,000,000 pions / 5,000,000 antipions
 - Reconstructed (exactly 1 track): 4,275,323 / 4,273,696
 - HighPurity: 4,254,289 (85,1%) / 4,252,279 (85,0%)
- Control distributions compared for full set of pions with full set of antipions
 - Very similar, small differences in tails (probably statistical)
- Misalignment introduced, refitted without outlier rejection
 - Gaussian smearing of localX of all TOB modules with $\sigma=20\mu\text{m}$
- Tight track and hit selection

Setup of APE estimation tool

- Group modules in different “sectors”:
12 in TIB, 16 in TOB
 - Separated by layers
 - Further separation by orientation (inwards, outwards pointing)
 - Further separation of $r\phi$ and stereo-modules
- Scale calculated correction by factor 0.6 to avoid overestimation
- At least 1000 entries per regarded residual resolution interval
- Result after 11 iterations shown
- Following plots show important quantities before (left plot) and after (right plot) iterative APE estimation procedure the sublayers
 - TIB layer 4 out (see influence of neighbouring misalignment)
 - TOB layer1 $r\phi$ in, TOB layer 4 out, TOB layer 6 in

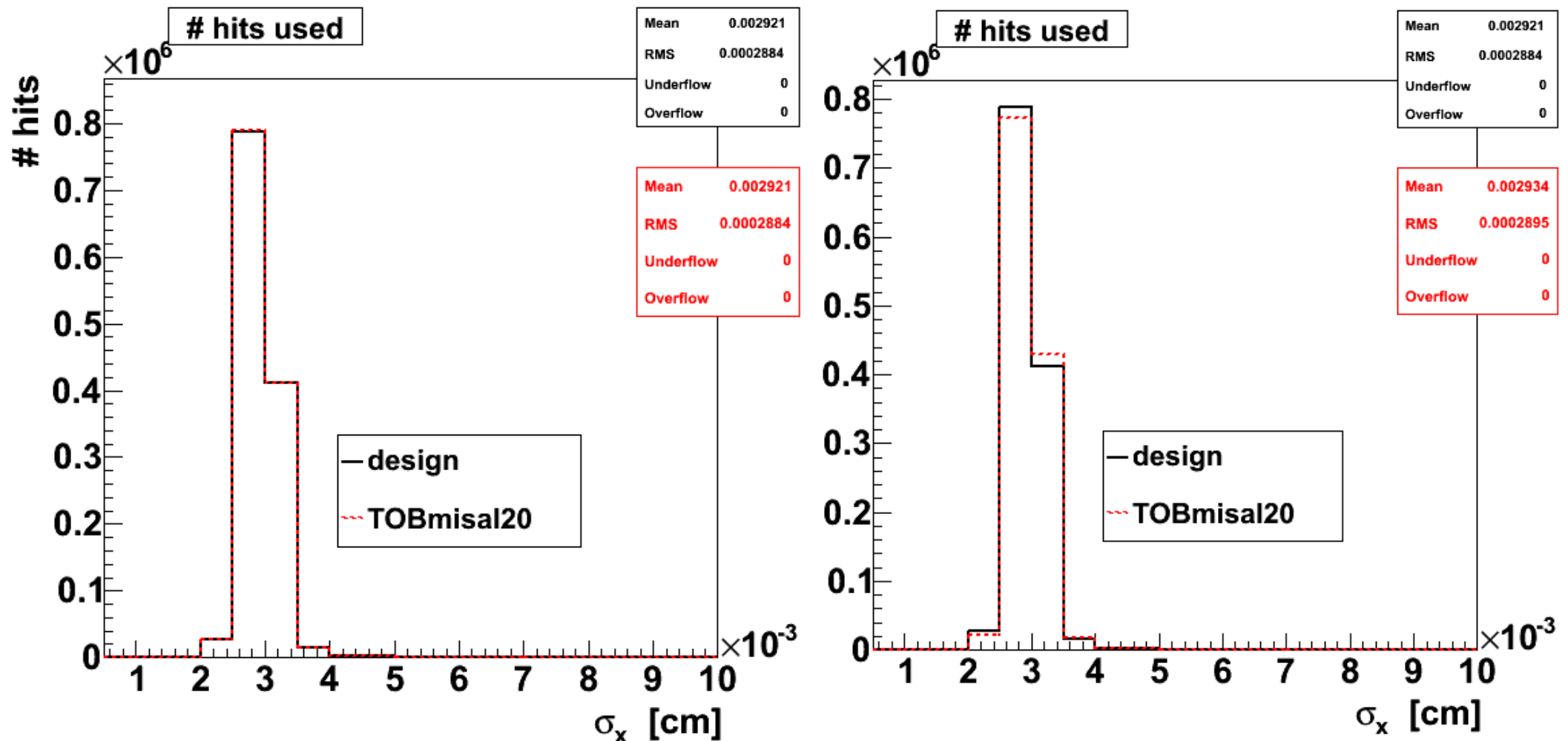
TIB layer 4 outwards, normalized residuals

- bla



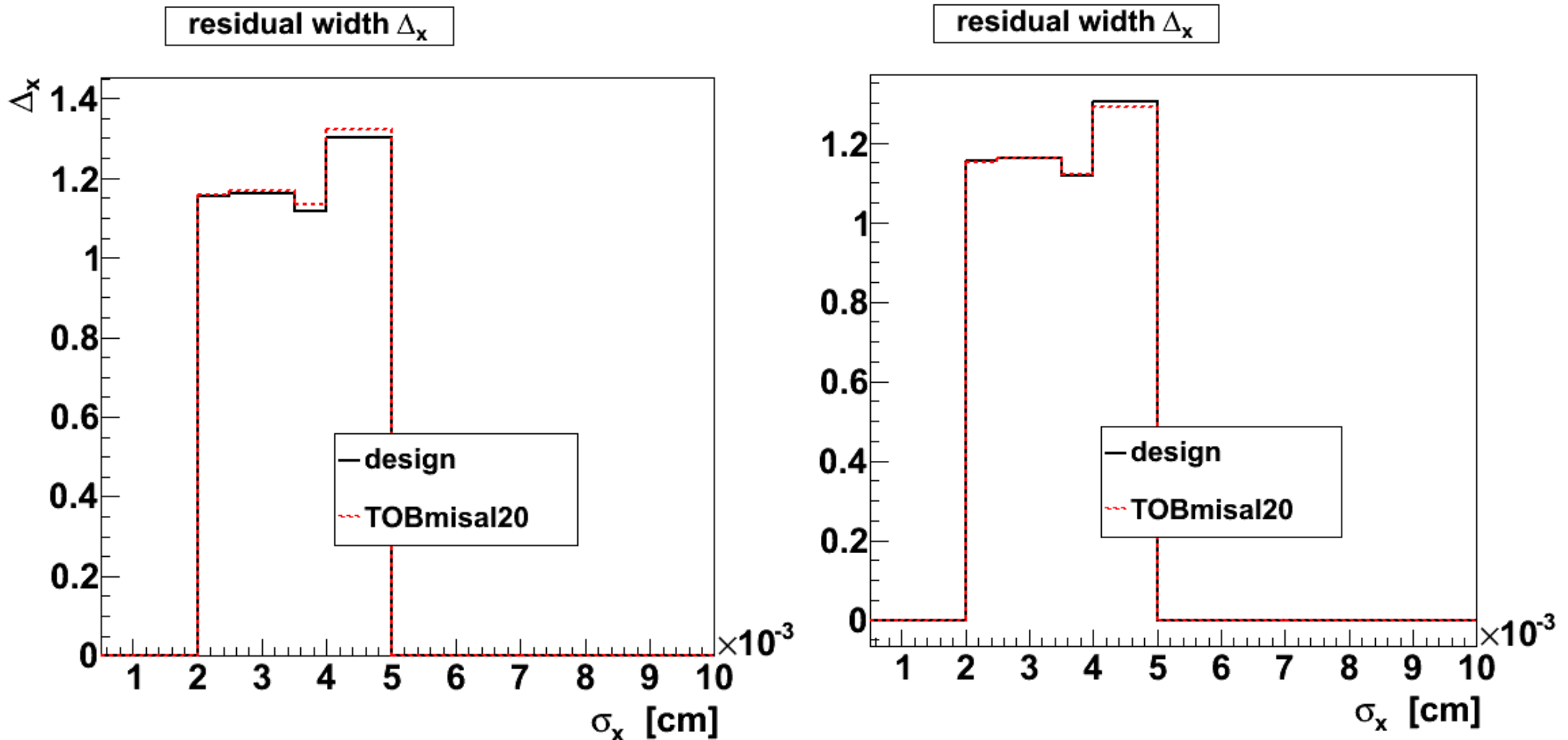
TIB layer 4 outwards, entries in residual resolution intervals

- bla



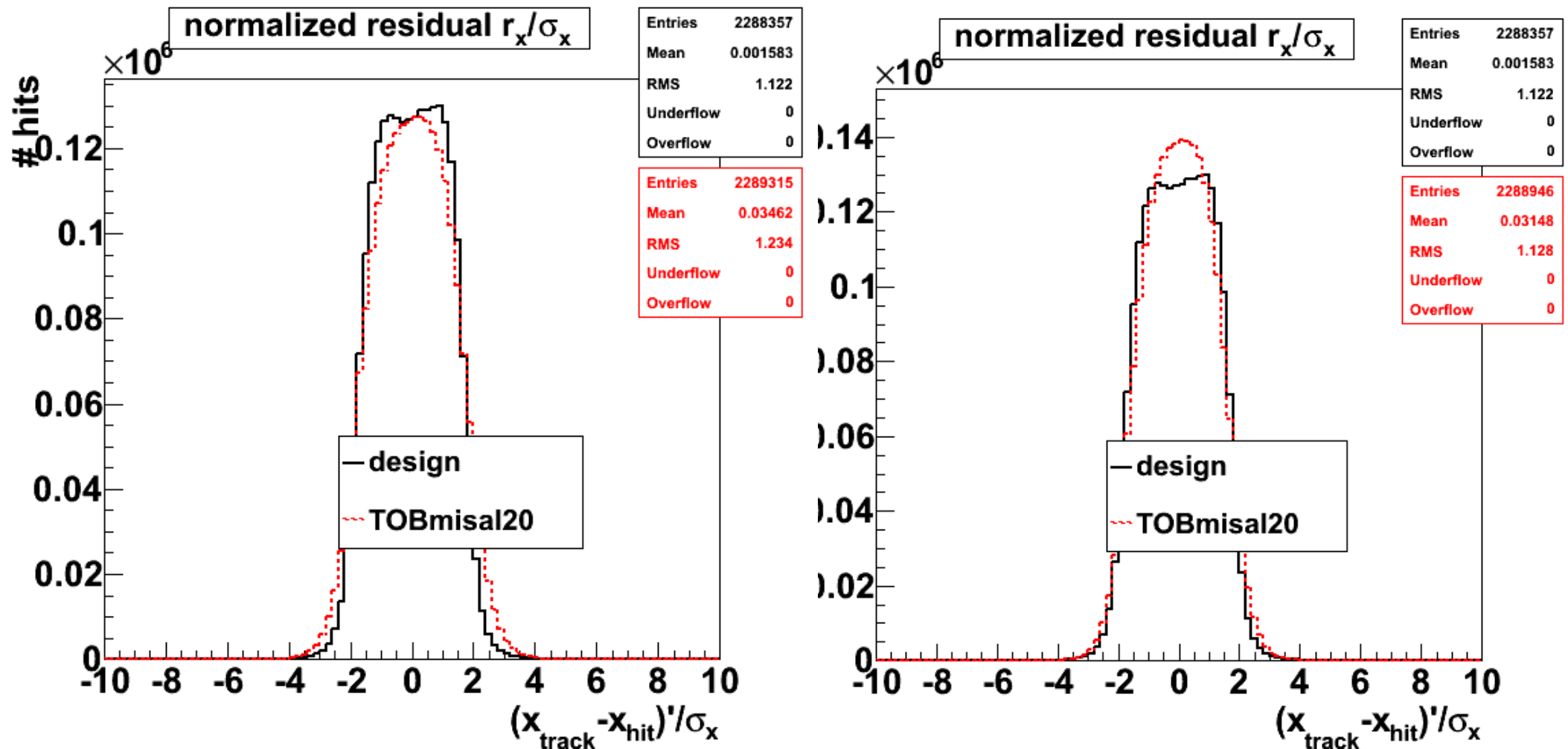
TIB layer 4 outwards, residual width wrt. residual resolution

- bla



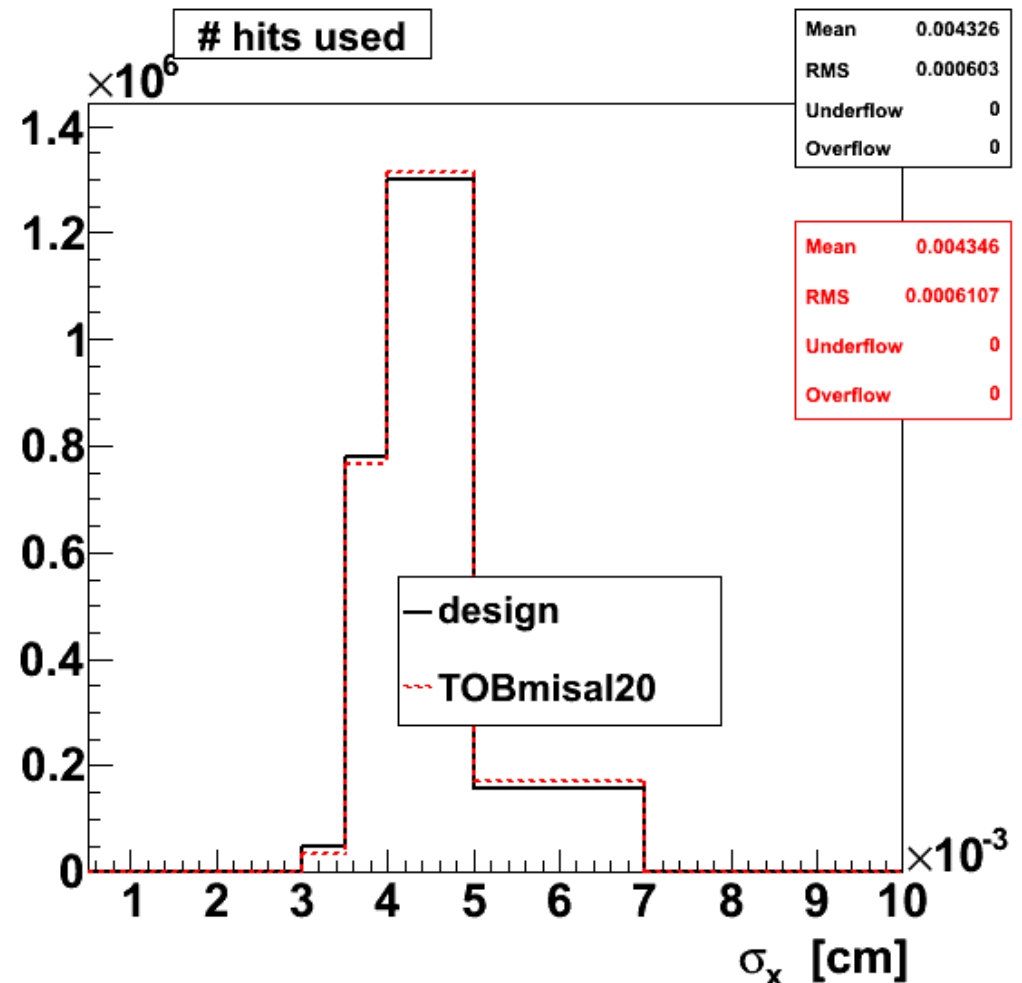
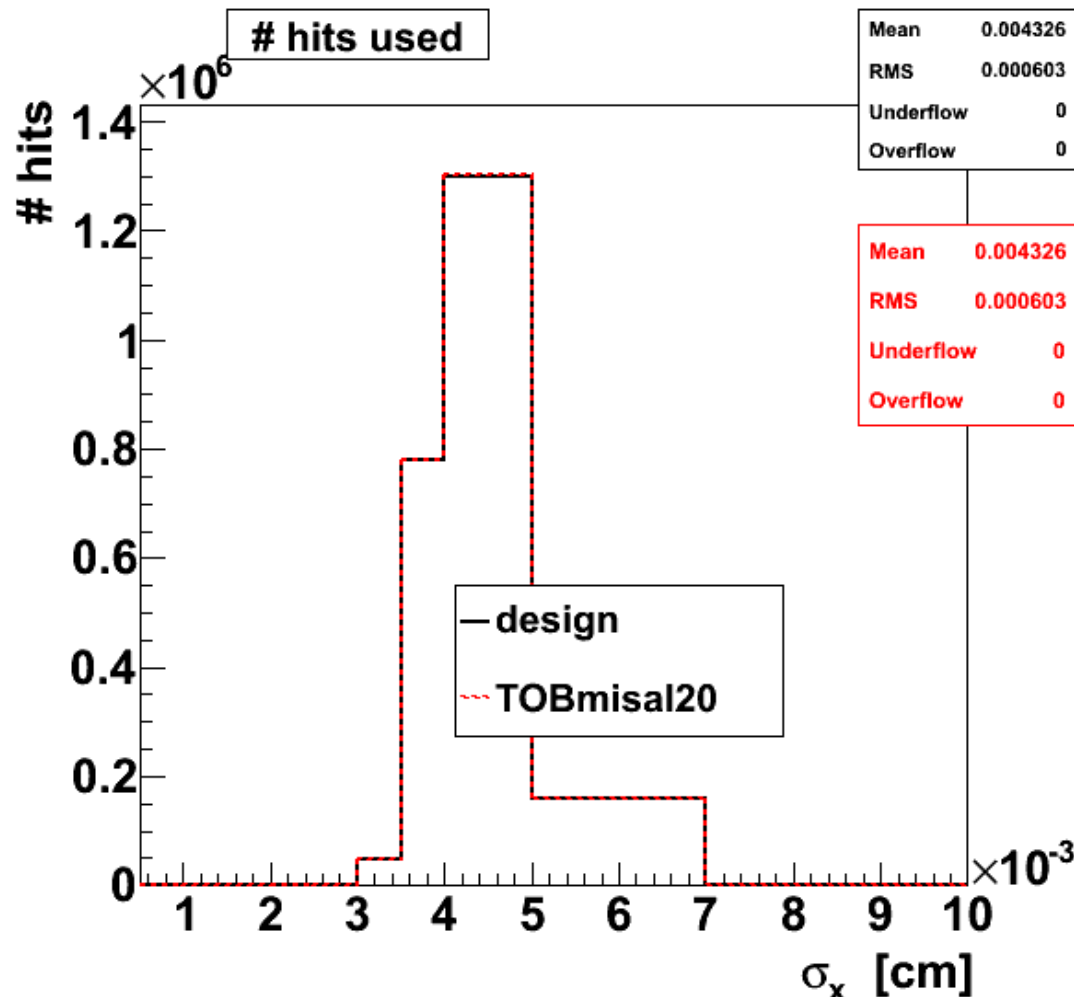
TOB layer 1 inwards, normalized residuals

- bla



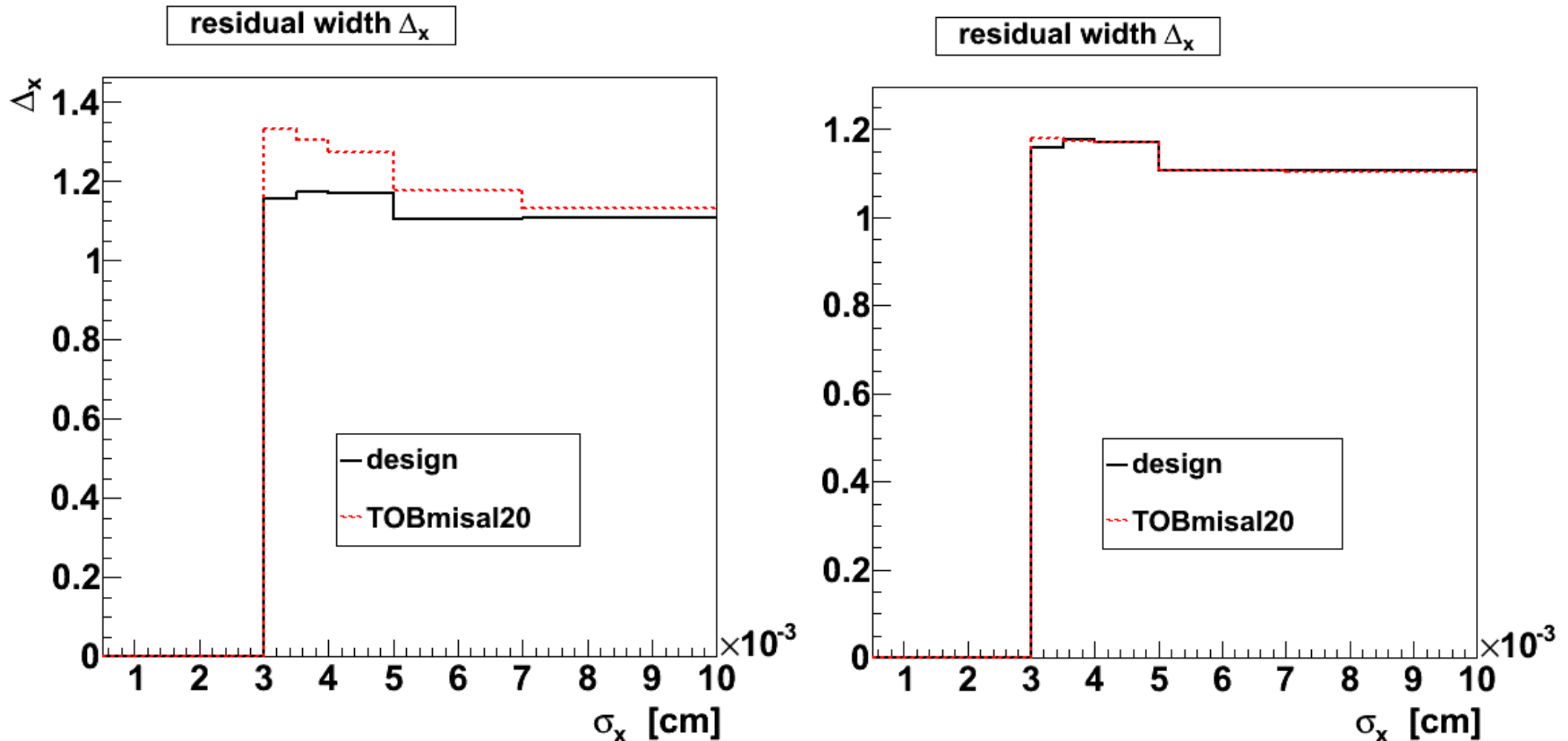
TOB layer 1 inwards, entries in residual resolution intervals

- bla



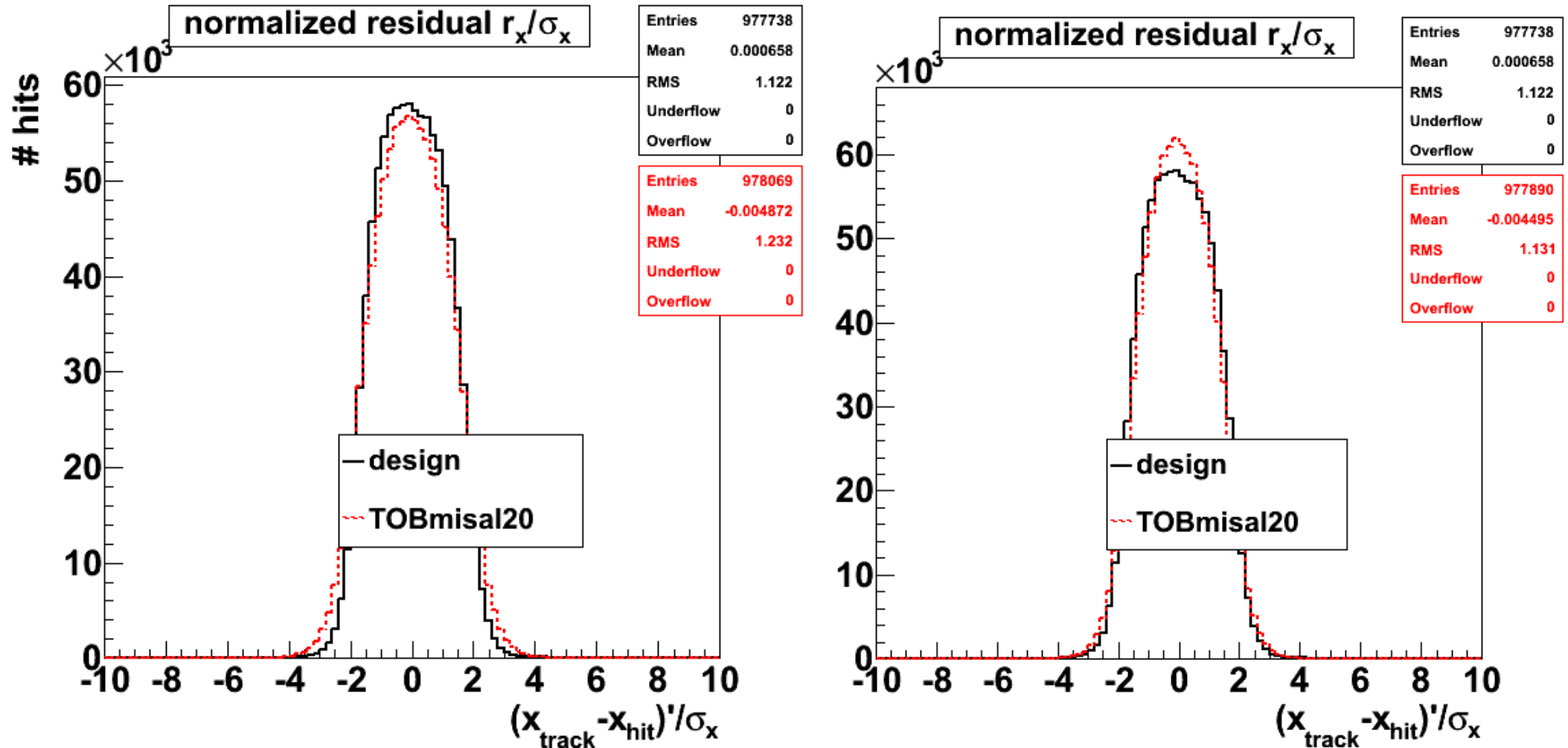
TOB layer 1 inwards, residual width wrt. residual resolution

- bla



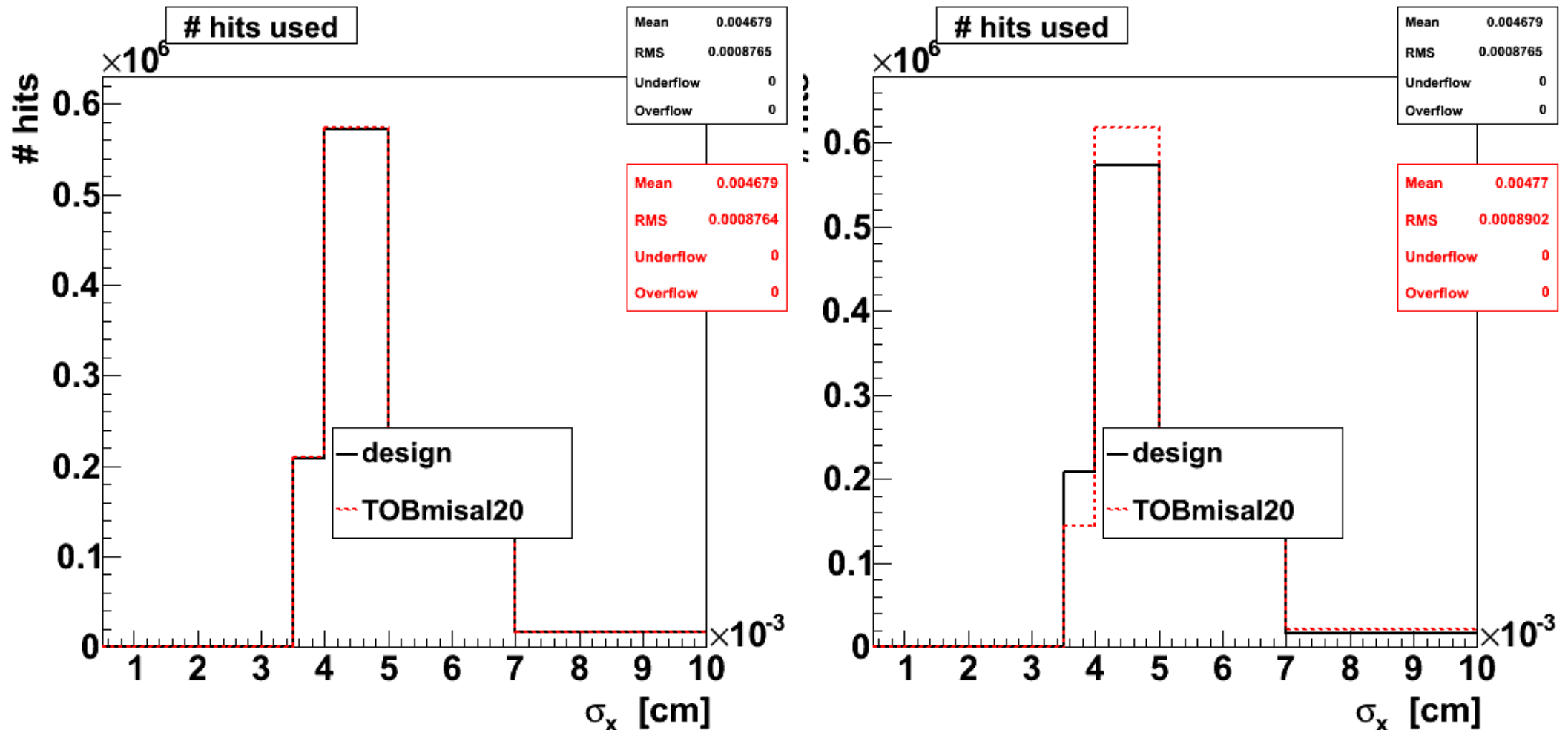
TOB layer 4 outwards, normalized residuals

- bla



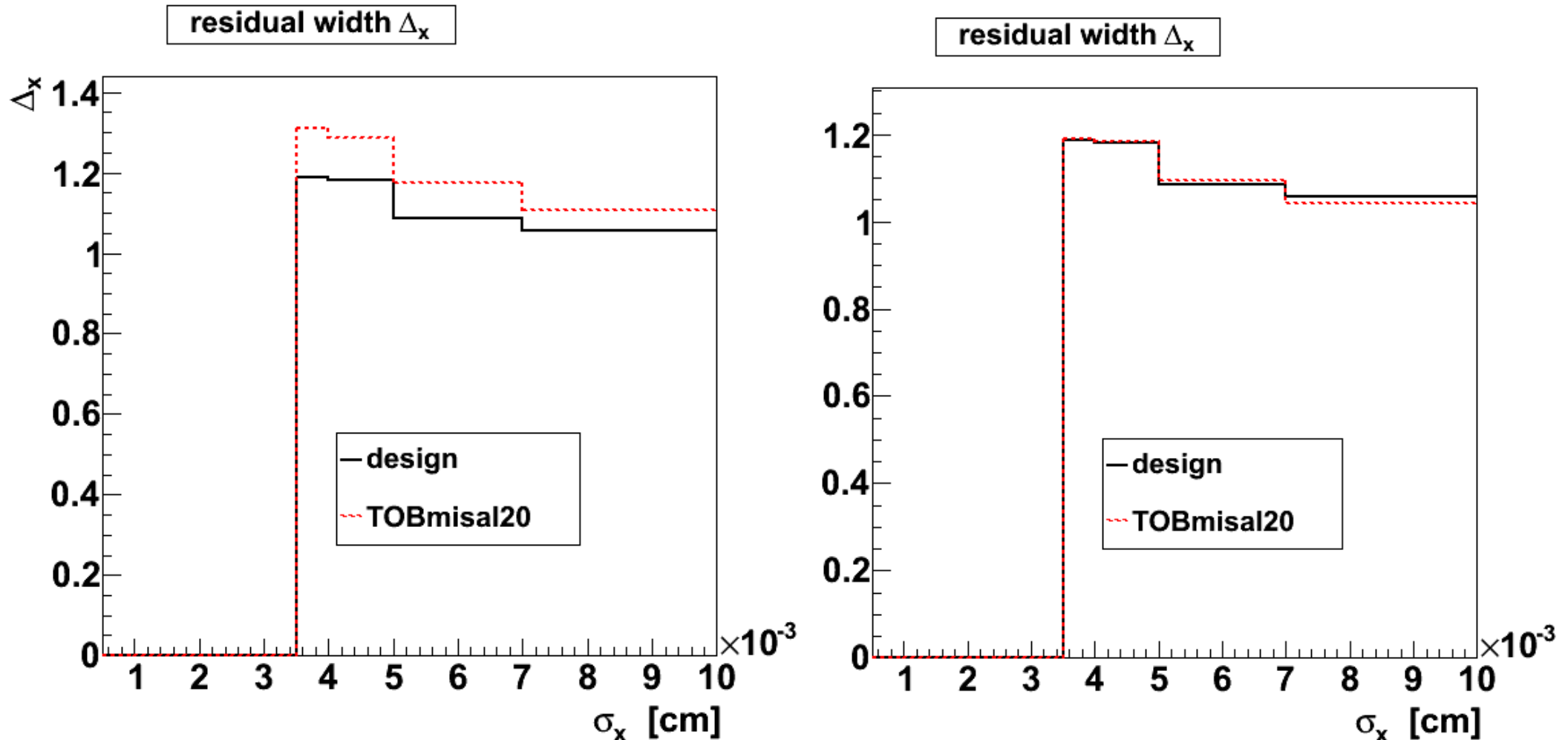
TOB layer 4 outwards, entries in residual resolution intervals

- bla



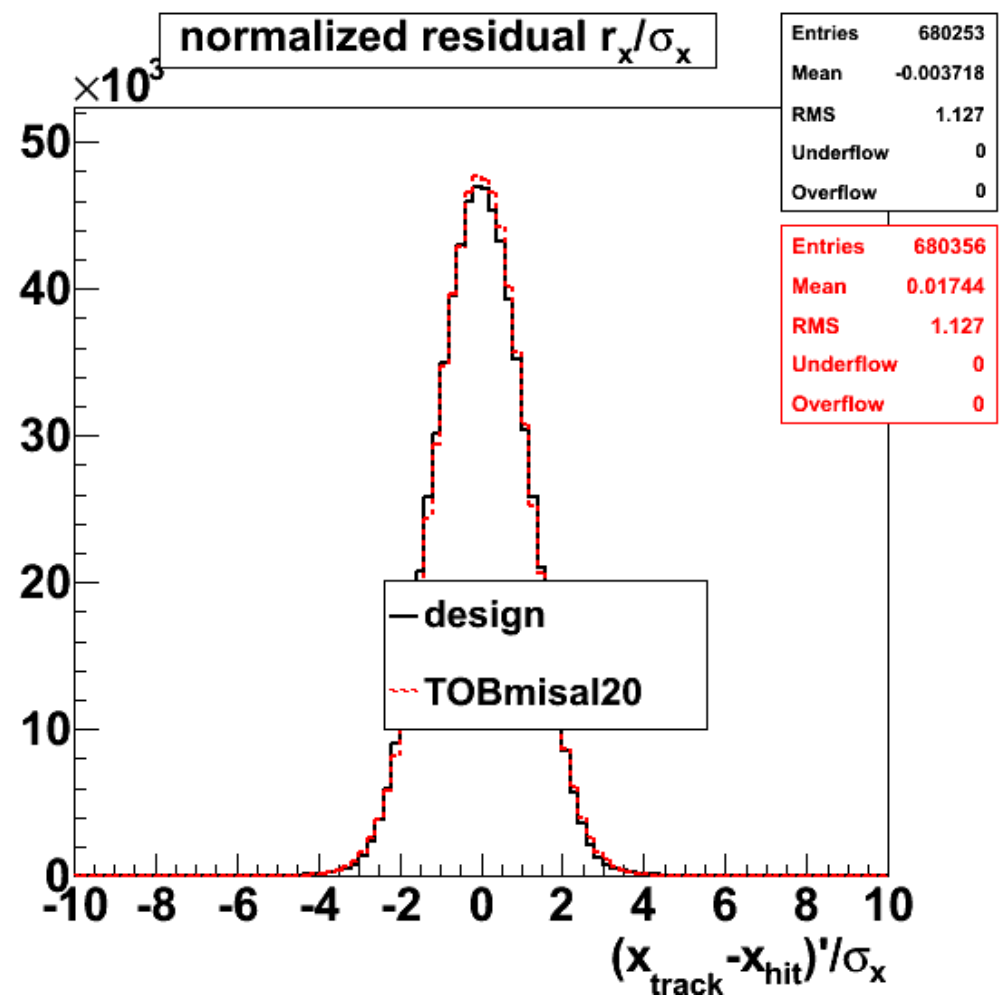
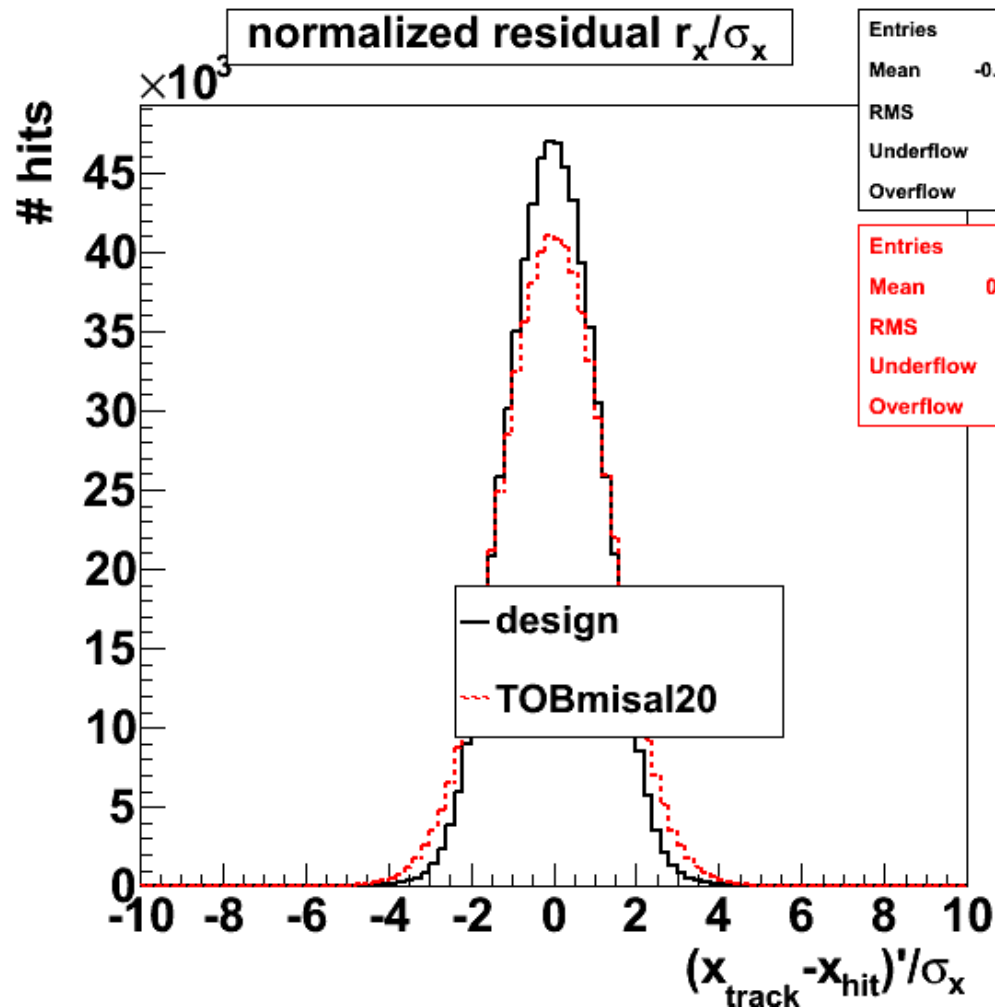
TOB layer 4 outwards, residual width wrt. residual resolution

- bla



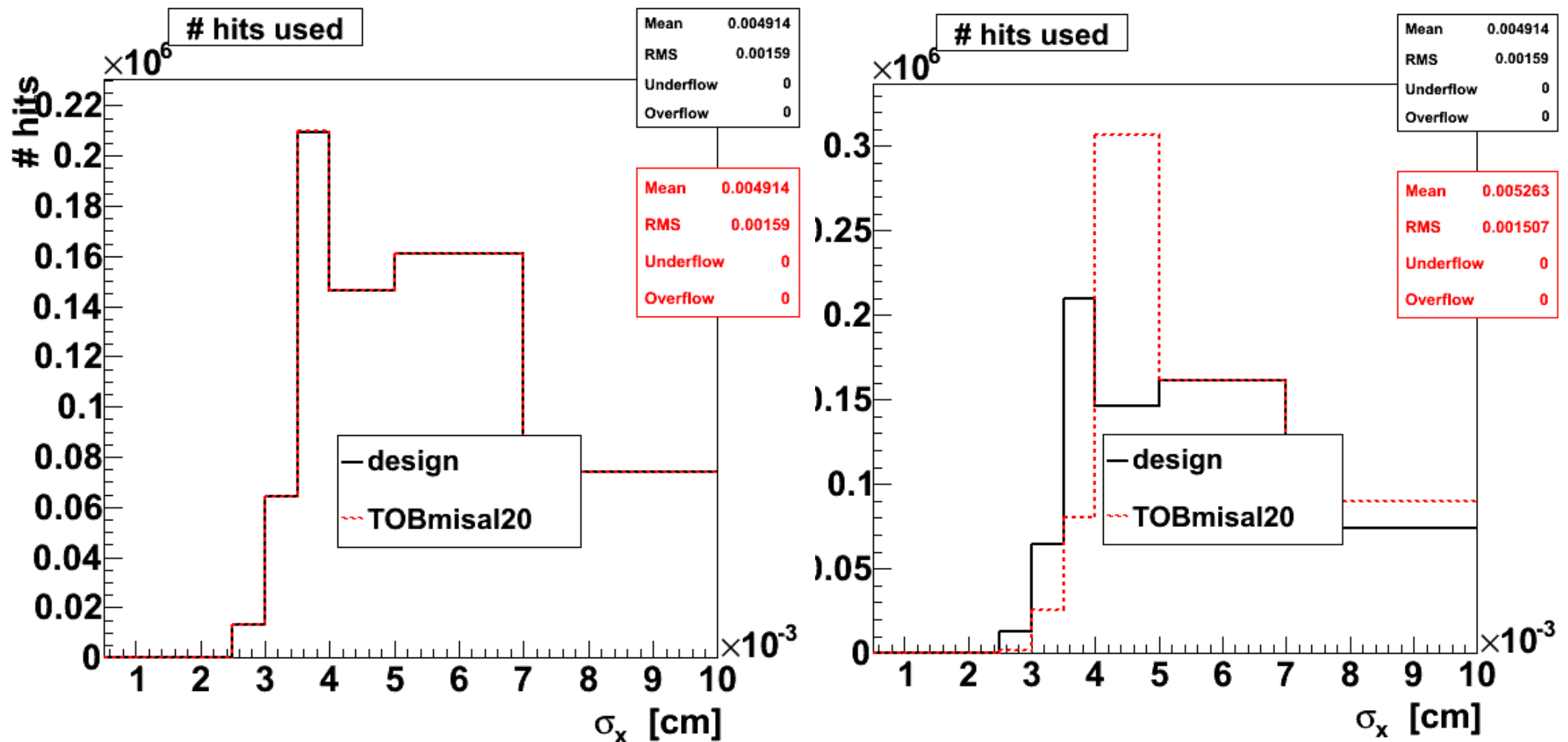
TOB layer 6 inwards, normalized residuals

- bla



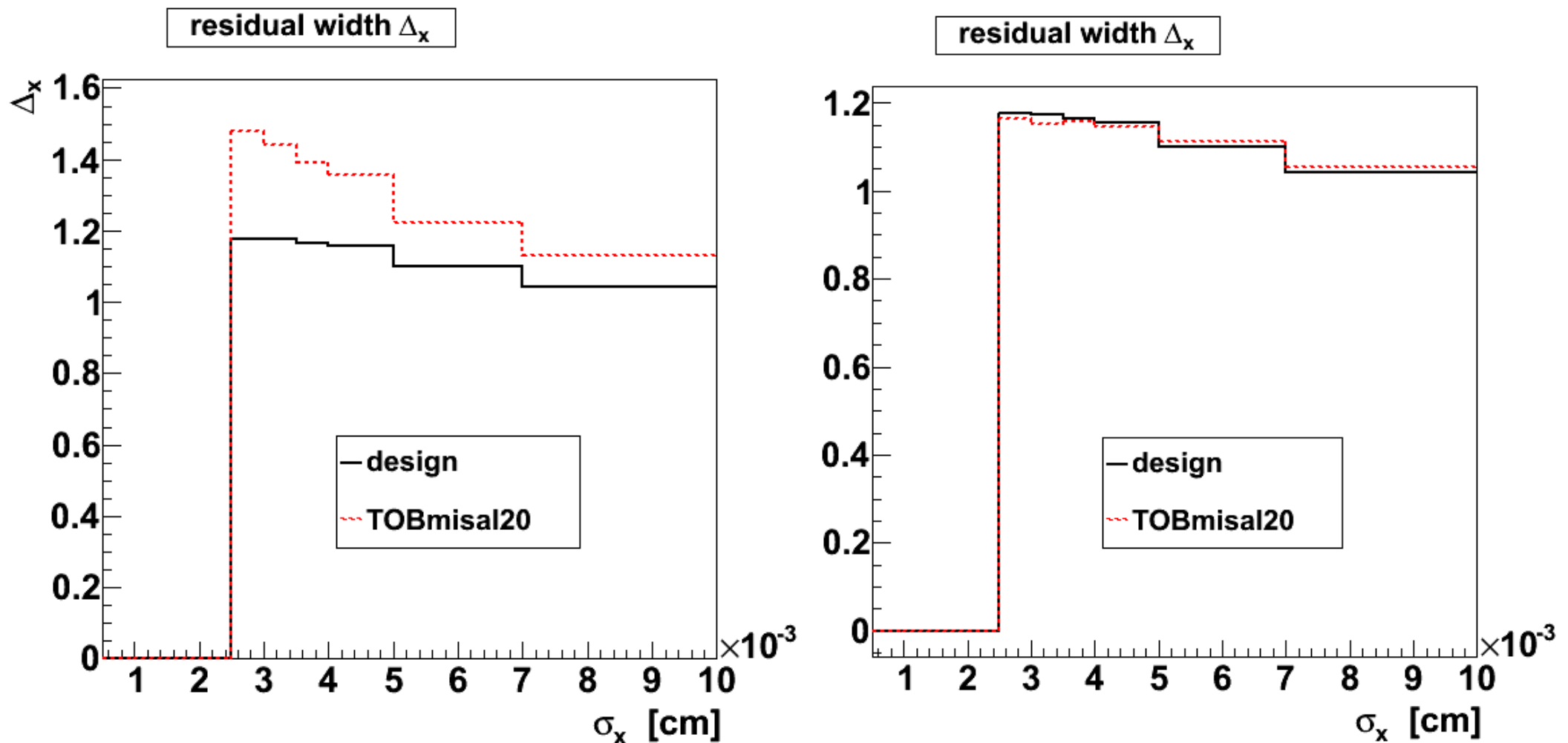
TOB layer 6 inwards, entries in residual resolution intervals

- bla



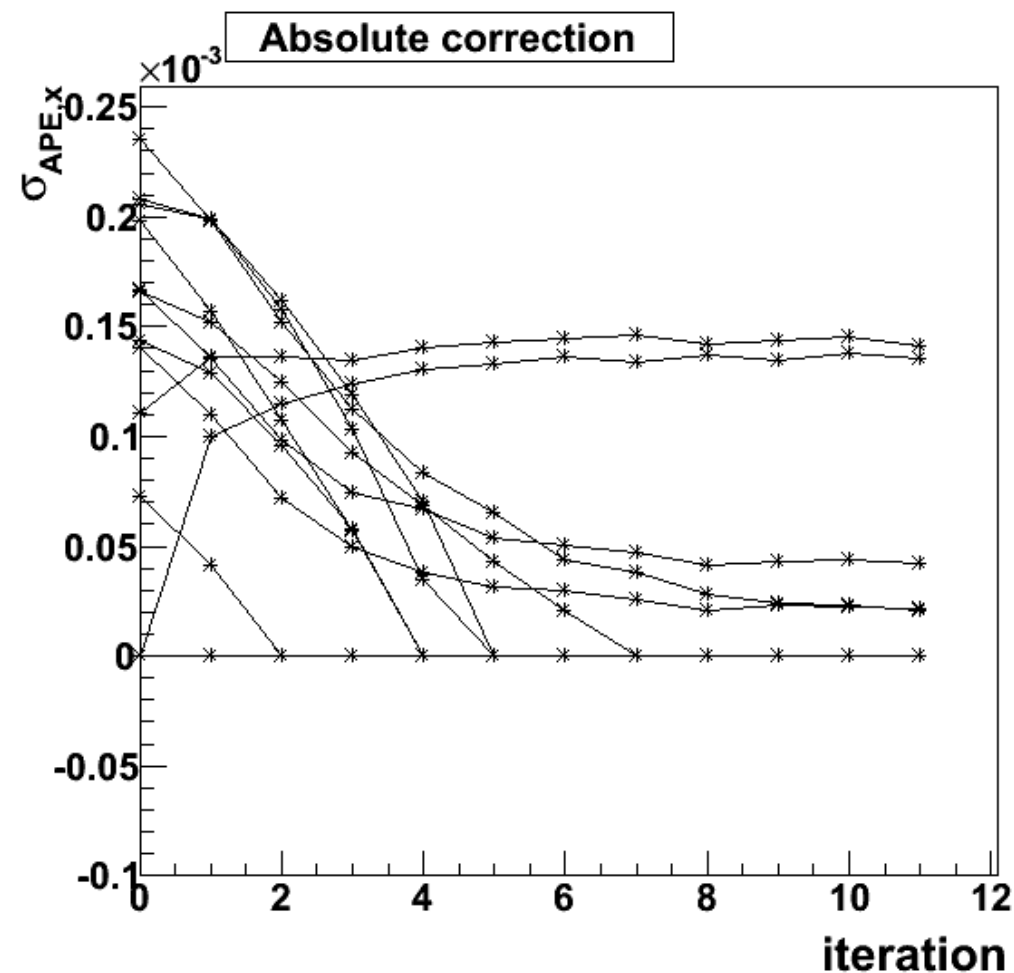
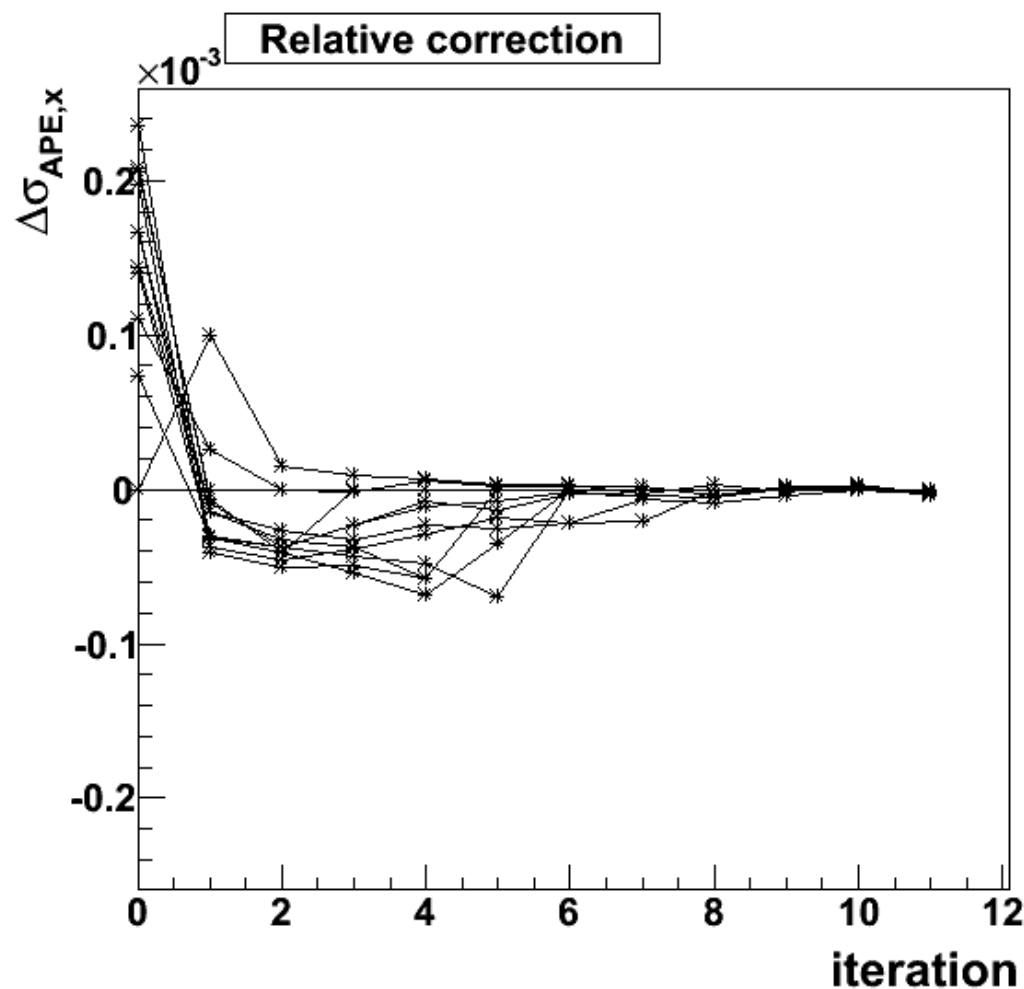
TOB layer 6 inwards, residual width wrt. residual resolution

- bla



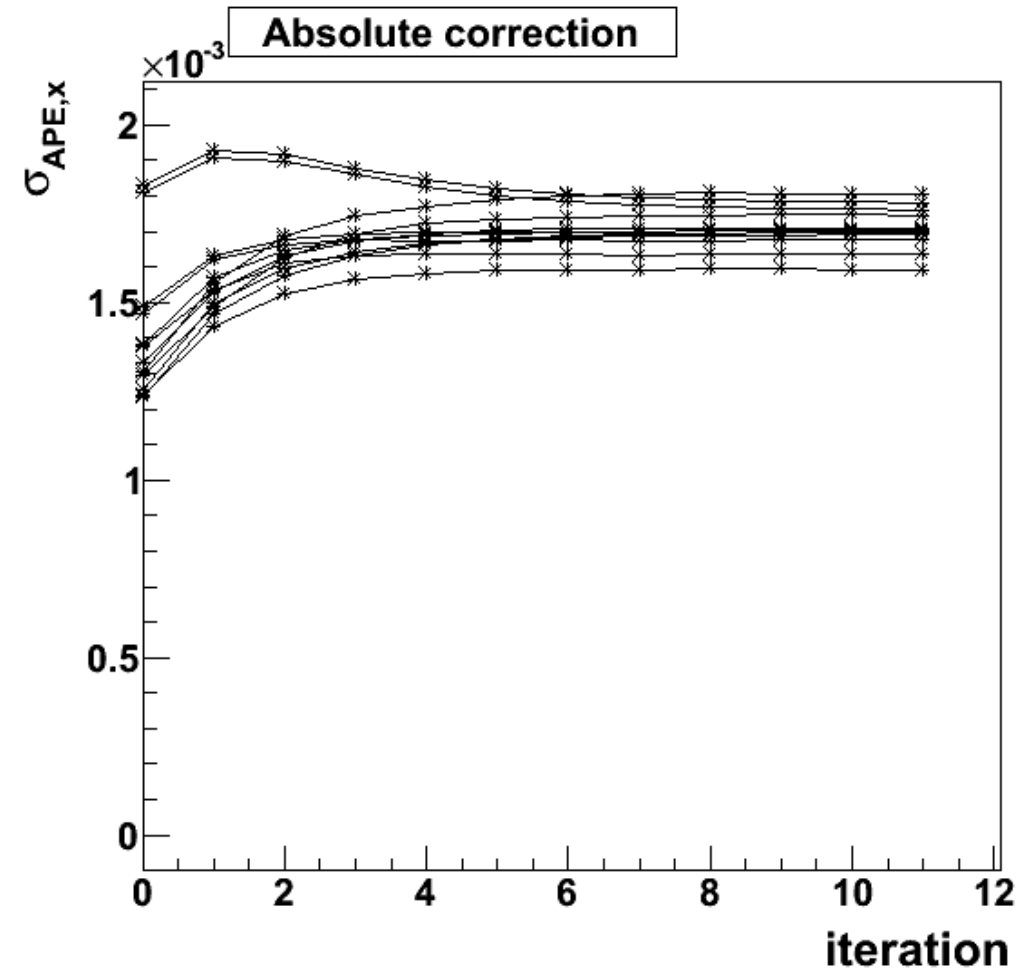
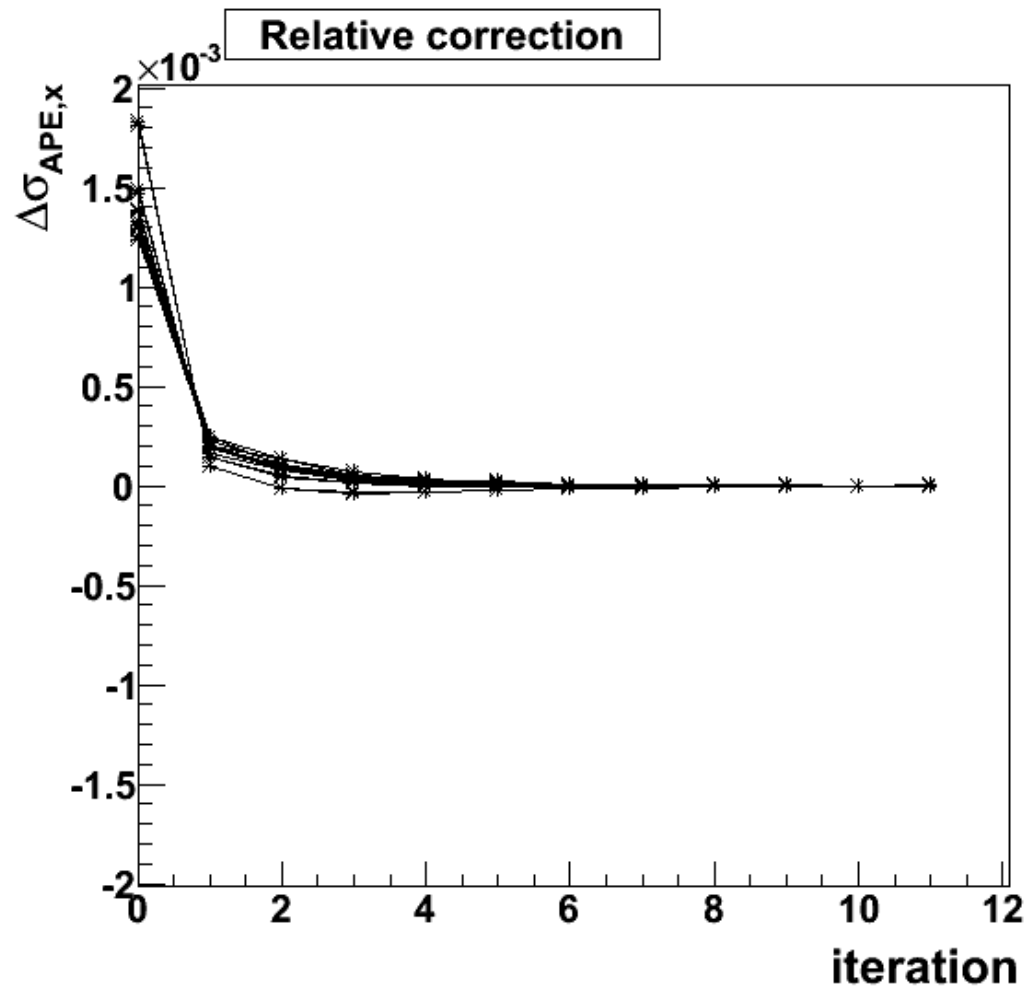
Result in TIB

- bla



Result in TOB

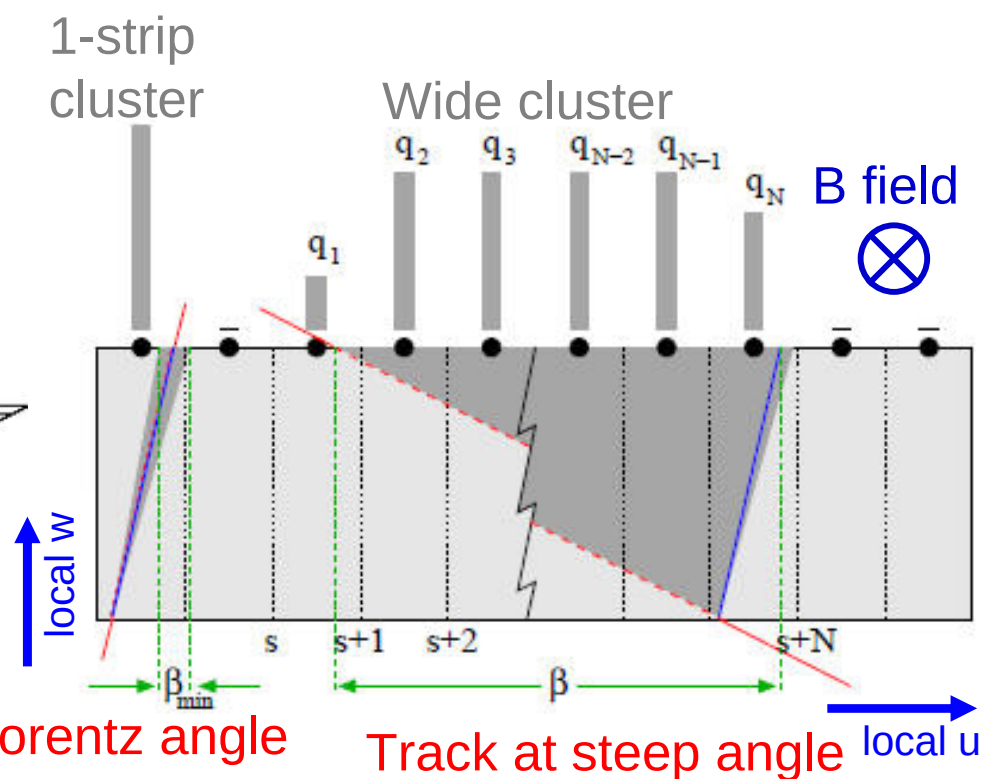
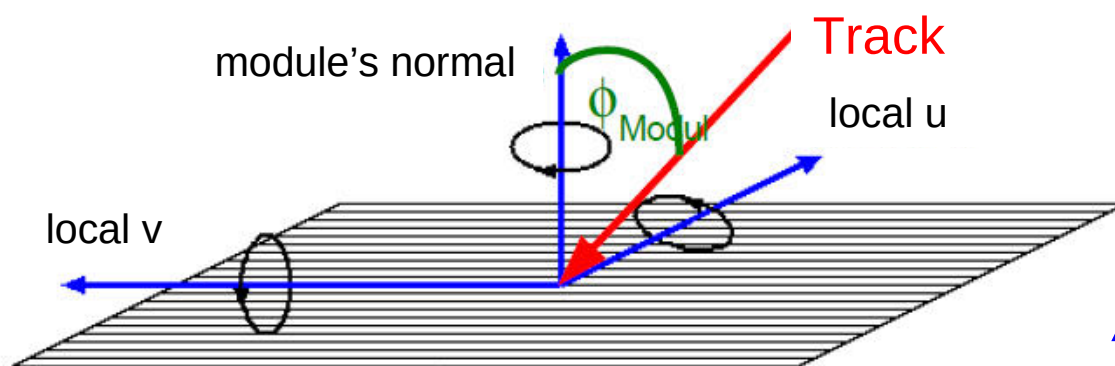
- bla



--- BACKUP ---

Incident angle & cluster width

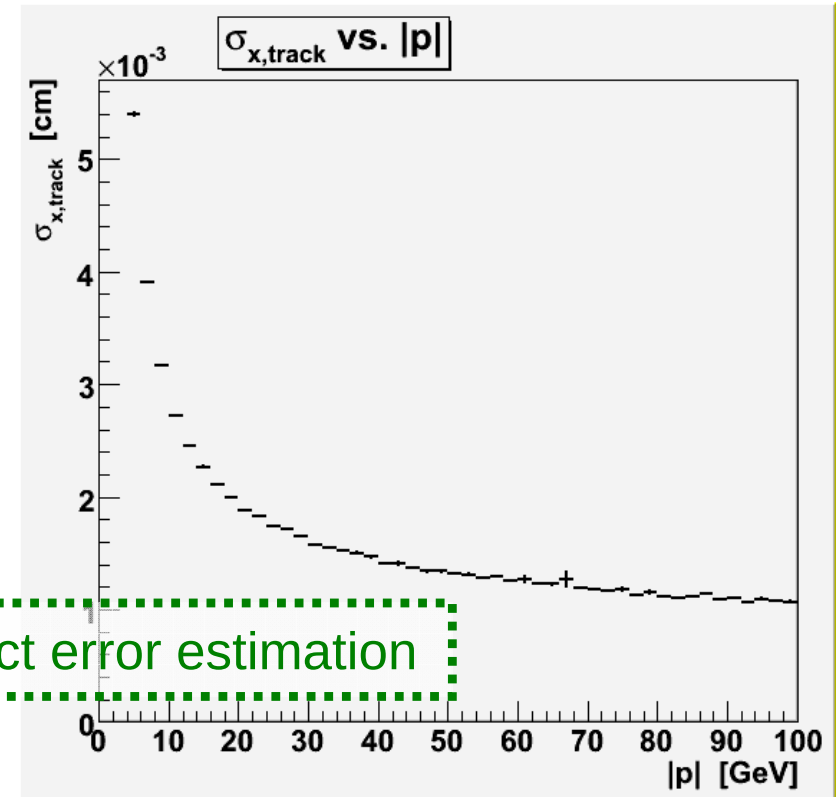
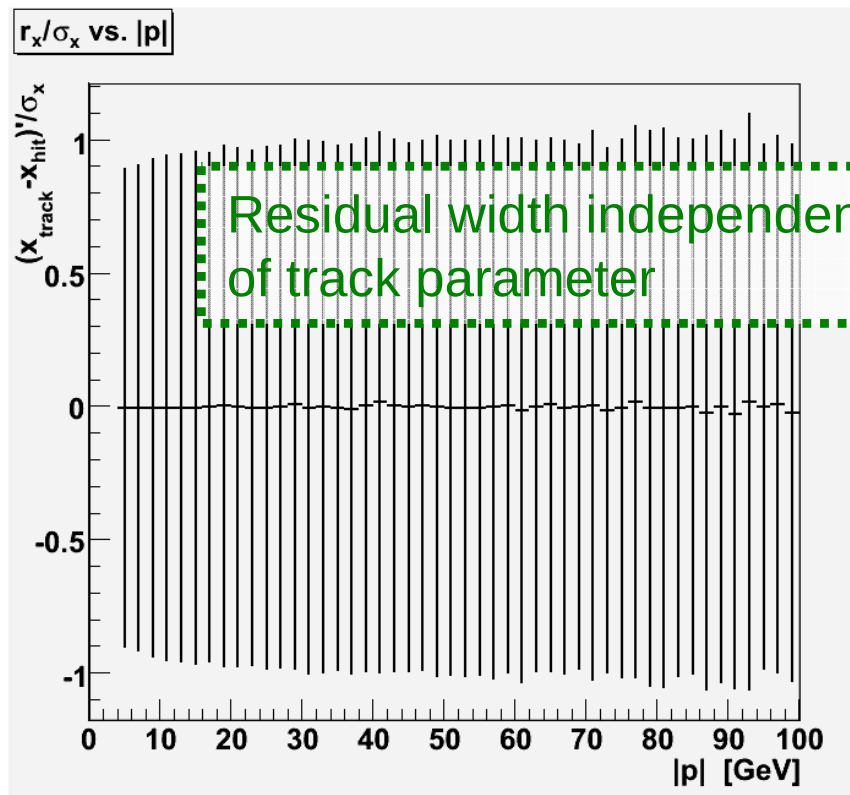
- No. of strips (pixels) with induced charge dependent on **incident angle perpendicular to strips** (related to module's normal)
 - B field $\rightarrow$ drift of charge asymmetric (**Lorentz angle**)
- **Parametrisation** of hit position and error adjusted for **collisions**
 - From interaction region
 - Small angles in general



Track at Lorentz angle
(minimal dispersion of charge carriers)

Dependency of residual width on track parameters

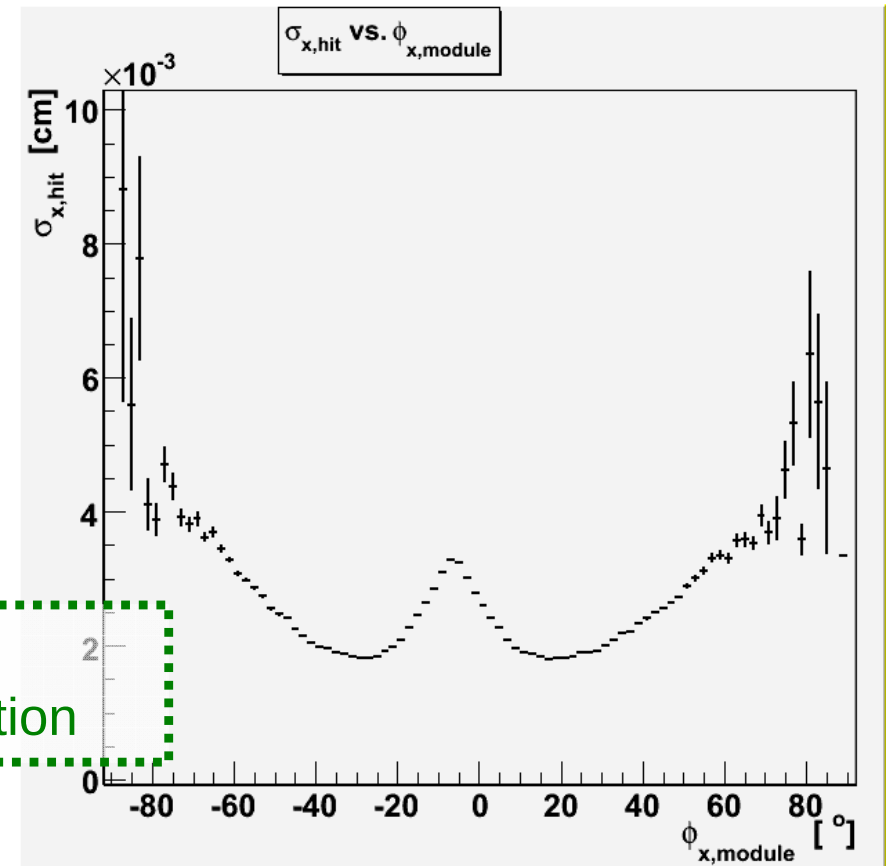
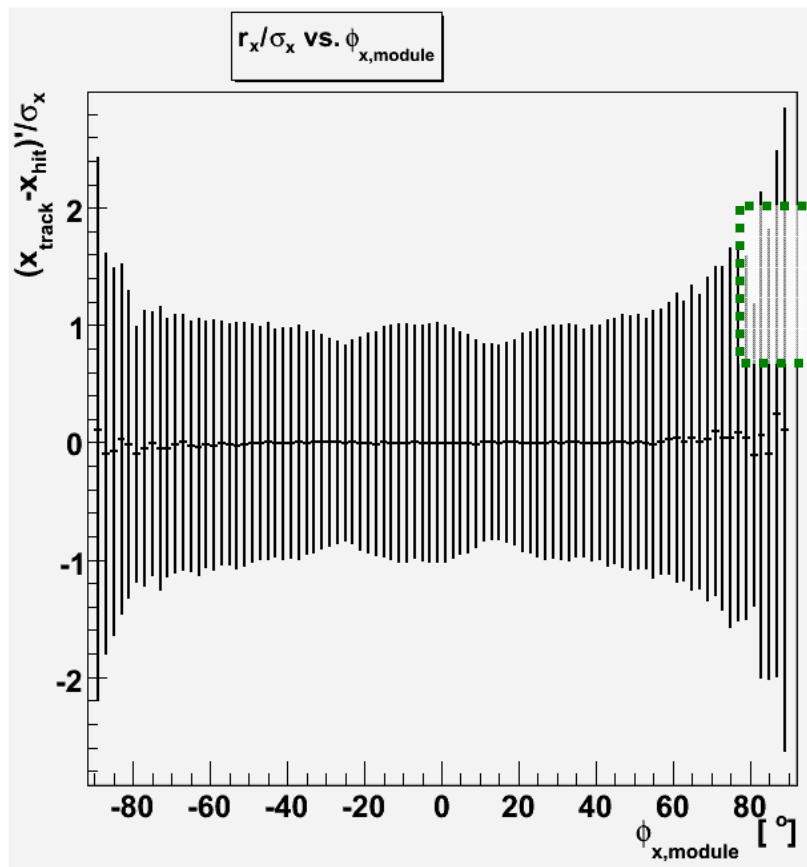
- Look at **relevant hit parameters** in **intervals** of track parameter
 - Error of track extrapolation:**
Decrease with increasing momentum,
Multiple scattering $\sigma_{MS} \sim p^{-1}$



- Width of normalised residual distribution:**
Error bars - RMS per momentum interval
almost **const. ≈ 1** for $p > 10$ GeV,
Mean close to 0

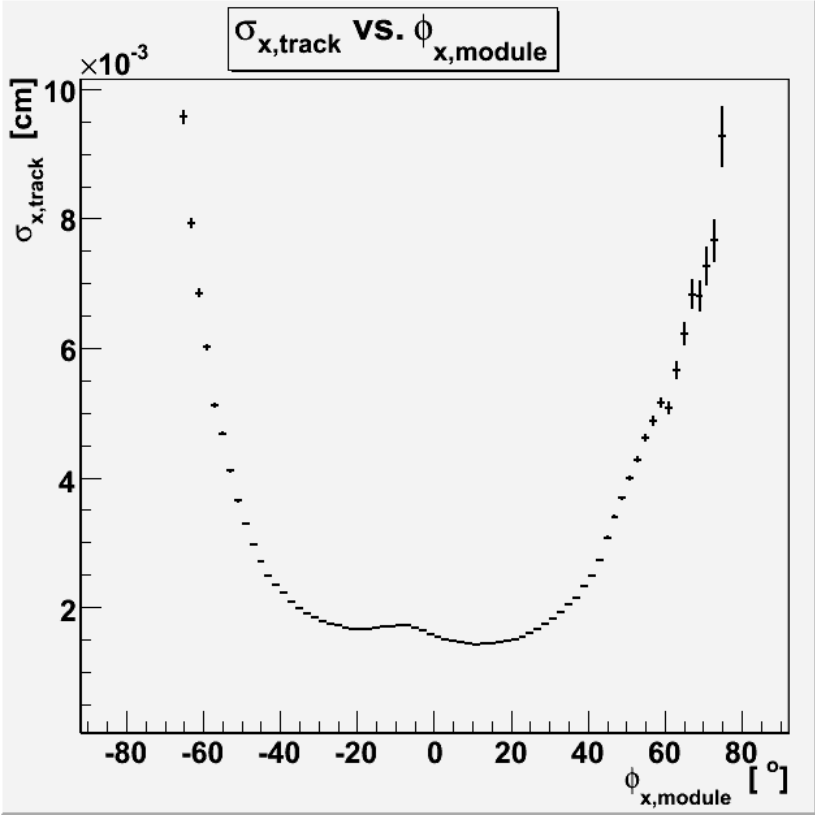
Dependency of residual width on hit parameters

- **Intervals** of hit parameter
 - **Hit error:**
maximum precision: **2-strip cluster**
→ minimal at **about $\pm 20^\circ$**
(Lorentz angle → asymmetry)



- **Normalised residual width:**
For **steep angles** clear broadening visible
→ **cut** on huge angles reasonable (expected)
Obvious discrepancy also for **other angles**
→ indication for **inaccurate error valuation**

Incident angle perpendicular to strips



Incident angle parallel to strips

